ATOMIC FORCE

MICROSCOPY

Featuring an innovational ergonomic design and improved electronics, this scientific microscope delivers atomic-scale resolution at a remarkably affordable price, making it an ideal choice for education as well as research. The NAMA-AFM offers educators an exceptional opportunity to introduce their students to many powerful SPM/AFM techniques.



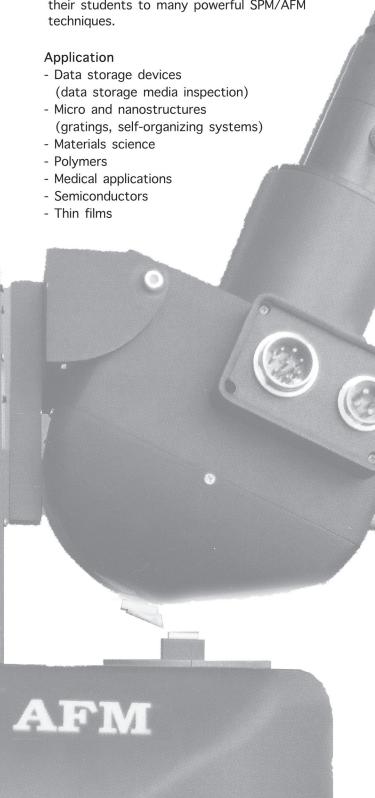
| Range of scanning X,Y | 10 | μm | | |
|---|------|-----|--|--|
| Range of scanning Z | 3 | μm | | |
| Lateral resolution | 0.13 | nm | | |
| Vertical resolution | 0.05 | nm | | |
| Scanning schema: Movable | | | | |
| sample under stationary probe | | | | |
| Scanner type: Piezo ceramic | | | | |
| Maximum sample size | 20 | mm | | |
| XY Micro positioning stage | 2.5 | μm | | |
| Embedded video system: visualization | | | | |
| on a PC connector via USB port from top and side. | | | | |
| Scanner DAC/ADC resolution | 16 | bit | | |

JJ Advantages

- Cost-effective platform offers simple upgrade path
- Excellent educational instrument with course curriculum

JJ Features

- Contact mode
- Noncontact mode
- Semi Contact



SCANNING TUNNELING

MICROSCOPY



Features:

- Automatic mechanism to approach sample
- Automatic sample and camera moving by software
- Capability of spectroscopy to verify the material type with I-Z and I-V modes at desired point of surface of sample
- Engraving of nanometer-scale surface by lithography (manually or by importing the pattern images from the desired file
- Ability of tilting (adjusting X, Y axis in sample)
- Capability to change size, angle and location of image by software without handling the sample and ability of automatic offset calculation
- Ability to analyze the image independently from the scanning
- Ability to apply custom filters in three stages on the data and possibility of retrieving the data
- Capability to take the repeated imaging without user intervention and possibility of changing conditions of imaging automatically
- Ability to export result, which is compatible with other softwares (txt. file)
- Ability to storage all data of scanning with image or spectroscopy curves.
- And more features such as:
- Advanced mechanical design with very low thermal drift and the ability to view online height and current during scanning
- Imaging capability in both constant height and constant current modes with minimum electronic noise.
- Ability to change the parameters of the PID, Current and voltage during imaging
- Provide 2D and 3D images at nanometer-scale simultaneously (such as biological molecules, DNA, Antibody and nanomaterial)
- Ability to display multiple clear and accurate 2D and 3D image files in order to compare them (for study on changing the status of polymers over the time
- Ability to measure the size of material on the image
- Hardware zoom capability for desired more detailed image.
- Software zoom capability for desired area
- Ability to customize the color of image file Specification



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A scanning tunneling microscope is a powerful tool for obtaining micrographs from conductive and semiconductive materials. The imaging technique has recently been improved for microscopy of nanostructured biomaterials on highly ordered atomic surfaces. We describe, here, high resolution imaging of individual IgM and IgG using a scanning tunneling microscope (Nama-STM) inaircondition. The biomolecules were immobilized on the surface of Highly Ordered Pyrolytic Graphite (HOPG). Obtained micro graphs could reveal structural details of immunoglobulins G and M on the atomically flat surfaces. Obtained results confirmed that STM could be more useful than other microscopy techniques for the analysis of single biomolecules.

J Advantages

- Expandable to suite user needs
- Designed for quick and reliable measurements by experts and novices alike
- Unique price/performance ratio for research and teaching
- Mechanical Stability
- Thermal drift balance
- Low Flectronic noise
- Ergonomic Design
- Windows-Based Powerful Software
- Easy Maintenance



STM Software

| Various charts of the scan data online | 2D view Image, Line graph, spectroscopy (I-V, I-Z) |
|---|--|
| Various charts of the image data offline | 2D view, 3D view, Line Profile, Color map |
| Various charts of the spectroscopy (I-V, I-Z)data offline | Line Graph, first and second derivative, |
| Noise reduction and feature enhancement | Data filtering in three levels |
| Lithography pattern | 16 Color BMP and .dxf files |
| View all maximum scan range and change parameter very user friendly | |
| Data export | TXT,BMP,JPEG,GIF, |
| Automatic image transfer to offline processing software | |
| NAMA Analyzer | |

ELECTRONICS

| Electronics size | 55*55*18 cm |
|-------------------------|---|
| Power supply | 220 V~/ 50 Hz/ 1A |
| Computer Interface | 16 bit Data Acquisition Hardware |
| Scan Speed | Up to 100 Line/s at 128 data point / line |
| Scan image rotation | 0 - 360° |
| Sample tilt | Automatically by software |
| Spectroscopy modes | Single point measurement |
| Spectroscopy data point | Up to 2000 |

STM Measurment

| Maximum Scan range | 8 μm (±4000nm) |
|----------------------|---|
| Maximum Z-range | $3 \mu m (\pm 1500 nm)$ |
| Derive resolution Z | 0.045 nm |
| Derive resolution XY | 0.12 nm |
| Current set point | 0.02 -100 nA in 3 pA steps |
| Imaging modes | Constant current(Topography), Constant Height (Current) |
| Spectroscopy modes | Current-Voltage, Current-Distance |
| Lithography modes | Bitmap, Vector and Manual |
| Tip voltage | ±10 V in 0.3 mV steps |
| Sample approach | Fully automatic and manually |
| Sample size | Max 20 mm diameter |